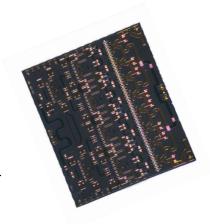


CMPA1C1D060D

60 W, 12.7 - 13.25 GHz, 40 V, GaN MMIC, Power Amplifier

Cree's CMPA1C1D060D is a gallium nitride (GaN) High Electron Mobility Transistor (HEMT) based monolithic microwave integrated circuit (MMIC) on a silicon carbide substrate, using a 0.25 µm gate length fabrication process. GaN-on-SiC has superior properties compared to silicon, gallium arsenide or GaN-on-Si, including higher breakdown voltage, higher saturated electron drift velocity and higher thermal conductivity. GaN HEMTs also offer greater power density and wider bandwidths compared to Si, GaAs, and GaN-on-Si transistors.



Typical Performance Over 12.7-13.25 GHz (T_c = 25°C)

Parameter	12.7 GHz	13.0 GHz	13.25 GHz	Units
Small Signal Gain	26.5	26.2	26	dB
P _{SAT} @ P _{IN} = 28 dBm	65	63	60	W
PAE @ P _{IN} = 28 dBm	29	28	27	%

Note: All data in this table is based on fixtured, CW performance.

Features

- 26 dB Small Signal Gain
- 60 W Typical P_{SAT}
- Operation up to 40 V
- · High Breakdown Voltage
- High Temperature Operation
- Size 0.209 x 0.240 x 0.004 inches

Applications

- Satellite Communications Uplink
- PTP Radio



Absolute Maximum Ratings (not simultaneous) at 25°C

Parameter	Symbol	Rating	Units	Conditions
Drain-source Voltage	V _{DSS}	84	V _{DC}	25°C
Gate-source Voltage	V _{GS}	-10, +2	V _{DC}	25°C
Storage Temperature	T _{STG}	-55, +150	°C	
Operating Junction Temperature	T _J	225	°C	
Maximum Forward Gate Current	I _{GMAX}	16.8	mA	25°C
Maximum Drain Current ¹	I _{DMAX}	1.8	Α	Stage 1, 25°C
Maximum Drain Current ¹	I _{DMAX}	3.6	Α	Stage 2, 25°C
Maximum Drain Current ¹	I _{DMAX}	9	Α	Stage 3, 25°C
Thermal Resistance, Junction to Case ²	$R_{\theta JC}$	1.12	°C/W	85°C, P _{DISS} = 118 W
Mounting Temperature (30 seconds)	T _s	320	°C	30 seconds

Note¹ Current limit for long term, reliable operation. Total current when biased from top and bottom drain pads.

Note² Eutectic die attach using 80/20 AuSn mounted to a 55 mil thick CuMoCu carrier.

Electrical Characteristics (Frequency = 12.7 GHz to 13.25 GHz unless otherwise stated; $T_c = 25^{\circ}C$)

Characteristics	Symbol	Min.	Тур.	Max.	Units	Conditions
DC Characteristics						
Gate Threshold	V _{TH}	-3.8	-2.8	-2.3	٧	$V_{DS} = 10 \text{ V, I}_{D} = 27 \text{ mA}$
Drain-Source Breakdown Voltage	$V_{_{BD}}$	84	100	-	٧	$V_{GS} = -8 \text{ V, I}_{D} = 27 \text{ mA}$
RF Characteristics ²						
Small Signal Gain	S21	-	27	-	dB	V_{DD} = 40 V, I_{DQ} = 0.45 A
Input Return Loss	S11	-	-15	-	dB	V_{DD} = 40 V, I_{DQ} = 0.45 A
Output Return Loss	S22	-	-5	-	dB	V_{DD} = 40 V, I_{DQ} = 0.45 A
Power Output	P _{out}	-	75	-	W	$V_{_{\mathrm{DD}}}$ = 40 V, $I_{_{\mathrm{DQ}}}$ = 0.45 A, CW, $P_{_{\mathrm{IN}}}$ = 30 dBm
Power Added Efficiency	PAE	-	30	-	%	$V_{_{\mathrm{DD}}}$ = 40 V, $I_{_{\mathrm{DQ}}}$ = 0.45 A, CW, $P_{_{\mathrm{IN}}}$ = 30 dBm
Power Gain	G_p	-	19	-	dB	$V_{_{\mathrm{DD}}}$ = 40 V, $I_{_{\mathrm{DQ}}}$ = 0.45 A, CW, $P_{_{\mathrm{IN}}}$ = 30 dBm
Output Mismatch Stress	VSWR	-	5:1	-	Ψ	No damage at all phase angles, $V_{DD} = 40 \text{ V, } I_{DO} = 0.45 \text{ A, } P_{OUT} = 30 \text{ W CW}$

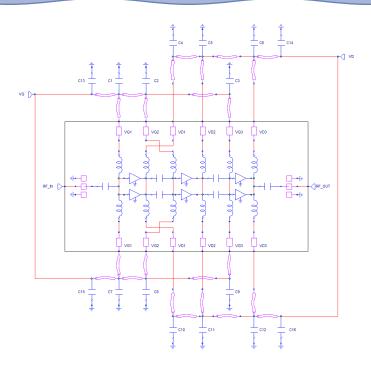
Notes:

¹ Scaled from PCM data.

 $^{^2}$ All data pulse tested on-wafer with Pulse Width = 10 μ s, Duty Cycle = 0.1%.



Block Diagram Showing Additional Capacitors for Operation Over 12.7 to 13.25 GHz



Designator	Description	Quantity
C1,C2,C3,C4,C5,C6,C7,C8,C9,C10,C11,C12	CAP, 51pF, +/-10%, SINGLE LAYER, 0.030", Er 3300, 100V, Ni/Au TERMINATION	12
C13,C14,C15,C16	CAP, 680pF, +/-10%, SINGLE LAYER, 0.070", Er 3300, 100V, Ni/Au TERMINATION	4

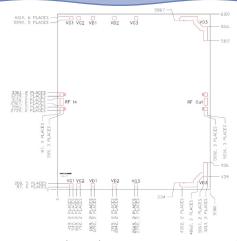
Notes:

¹ The input, output and decoupling capacitors should be attached as close as possible to the die-typical distance is 5 to 10 mils with a maximum of 15 mils.

² The MMIC die and capacitors should be connected with 2 mil gold bond wires.



Die Dimensions (units in microns)



Overall die size $5300 \times 6100 (+0/-50)$ microns, die thickness 100 (+/-10) microns. All Gate and Drain pads must be wire bonded for electrical connection.

Pad Number	Function	Description	Pad Size (in)	Note
1	RF_IN	RF-Input pad. Matched to 50 ohm	125x250	3
2	VG1 bottom	Gate control for stage1. Vg = -2.0 to -3.5 V	125x125	1,2
3	VG1 top	Gate control for stage1. Vg = -2.0 to -3.5 V	125x125	1,2
4	VG2 bottom	Gate control for stage2. Vg = -2.0 to -3.5 V	125x125	1,2
5	VG2 top	Gate control for stage2. Vg = -2.0 to -3.5 V	125x125	1,2
6	VD1 bottom	Drain control for stage1. Vd = 40 V	125x125	1
7	VD1 top	Drain control for stage1. Vd = 40 V	125x125	1
8	VD2 bottom	Drain control for stage2. Vd = 40 V	125x125	1
9	VD2 top	Drain control for stage2. Vd = 40 V	125x125	1
10	VG3 bottom	Gate control for stage3. Vg = -2.0 to -3.5 V	125x125	1,2
11	VG3 top	Gate control for stage3. Vg = -2.0 to -3.5 V	125x125	1,2
12	VD3 bottom	Drain control for stage3. Vd = 40 V	540x150	1
13	VD3 top	Drain control for stage3. Vd = 40 V	150x500	1
14	RF_OUT	RF-Output pad. Matched to 50 ohm	125x250	3

Notes:

Die Assembly Notes:

- Recommended solder is AuSn (80/20) solder. Refer to Cree's website for the Eutectic Die Bond Procedure application note at http://www.cree.com/~/media/Files/Cree/RF/Application%20Notes/Appnote%202%20Eutectic.pdf
- · Vacuum collet is the preferred method of pick-up.
- · The backside of the die is the Source (ground) contact.
- Die back side gold plating is 5 microns thick minimum.
- Thermosonic ball or wedge bonding are the preferred connection methods.
- · Gold wire must be used for connections.
- Use the die label (XX-YY) for correct orientation.

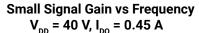
¹ Attach bypass capacitor to pads 2-13 per aplications circuit

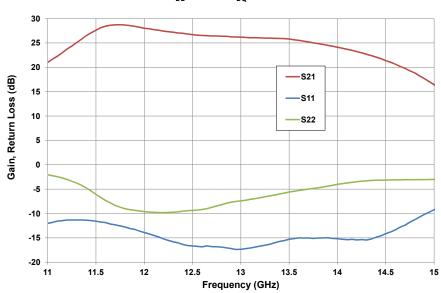
² VG1&2&3 top and bottom are connected internally, so it would be enough to connect either one for proper operation

³ The RF Input and Output pads have a ground-signal-ground with a nominal pitch of 10 mil (250 um). The RF ground pads are 125 x 250 microns

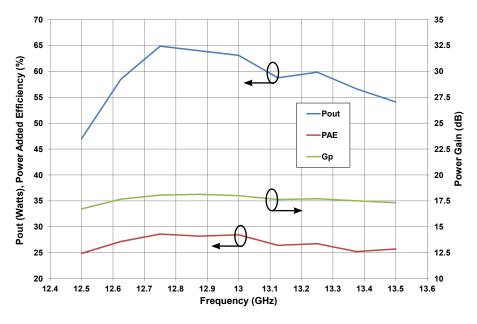


Typical Performance of the CMPA1C1D060D



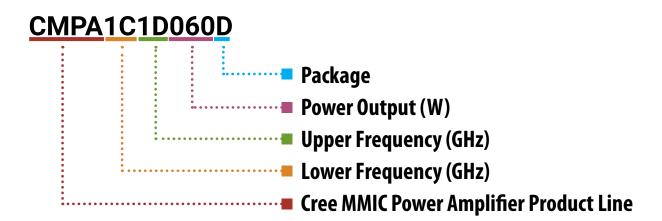


Output Power & PAE vs Frequency V_{DD} = 40 V, I_{DQ} = 0.45 A, P_{IN} = 28 dBm





Part Number System



Parameter	Value	Units
Lower Frequency	12.7	GHz
Upper Frequency ¹	13.25	GHz
Power Output	60	W
Package	Bare Die	-

Table 1.

Note¹: Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

Character Code	Code Value
А	0
В	1
С	2
D	3
E	4
F	5
G	6
Н	7
J	8
K	9
Examples:	1A = 10.0 GHz 2H = 27.0 GHz

Table 2.



Product Ordering Information

Order Number	Description	Unit of Measure
CMPA1C1D060D	GaN MMIC, Bare Die	Each



Disclaimer

Specifications are subject to change without notice. Cree, Inc. believes the information contained within this data sheet to be accurate and reliable. However, no responsibility is assumed by Cree for its use or for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Cree. Cree makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose. "Typical" parameters are the average values expected by Cree in large quantities and are provided for information purposes only. These values can and do vary in different applications, and actual performance can vary over time. All operating parameters should be validated by customer's technical experts for each application. Cree products are not designed, intended, or authorized for use as components in applications intended for surgical implant into the body or to support or sustain life, in applications in which the failure of the Cree product could result in personal injury or death, or in applications for the planning, construction, maintenance or direct operation of a nuclear facility. CREE and the CREE logo are registered trademarks of Cree, Inc.

For more information, please contact:

Cree, Inc. 4600 Silicon Drive Durham, North Carolina, USA 27703 www.cree.com/RF

Sarah Miller Marketing Cree, RF Components 1.919.407.5302

Ryan Baker Marketing & Sales Cree, RF Components 1.919.407.7816

Tom Dekker Sales Director Cree, RF Components 1.919.407.5639

www.cree.com/RI